Welcome to Galaxy Examinator reports

Date: Tue Sep 3 11:26:05 2024
Product :
LotID :

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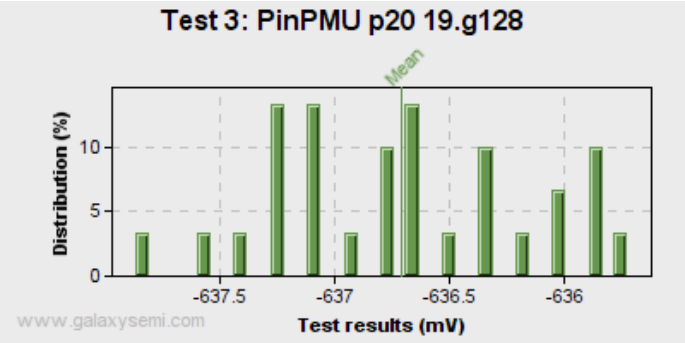
Tests Statistics

Test	Name	Type	Low L.	High L.	Source	Execs	Fails	Mean	Sigma	Cp	Cpk	Yield
0	Functional_T1	F	n/a .	n/a .	Samples	30	0	n/a .	n/a .	n/a .	n/a .	100.00 %
1	Functional_T5	P	n/a .	n/a .	Summary	2	0	n/a .	0	n/a .	n/a .	100.00 %
1	Functional_T2	F	n/a .	n/a .	Samples	30	0	n/a .	n/a .	n/a .	n/a .	100.00 %
2	Functional_T5	P	n/a .	n/a .	Summary	2	0	n/a .	0	n/a .	n/a .	100.00 %
2	Functional_T3	F	n/a .	n/a .	Samples	30	0	n/a .	n/a .	n/a .	n/a .	100.00 %
3	PinPMU p20 19.g128	P	−1200 mV	−100 mV	Samples	30	0	−636.705 mV	0.56067 mV	327.0	319.1	100.00 %
4	PinPMU p21 19.g126	P	−1200 mV	−100 mV	Samples	30	0	−636.888 mV	0.499823 mV	366.8	358.1	100.00 %
5	PinPMU p22 19.e126	P	−1200 mV	−100 mV	Samples	30	0	−636.739 mV	0.527604 mV	347.5	339.1	100.00 %
6	PinPMU p23 19.e124	P	−1200 mV	−100 mV	Samples	30	0	−636.87 mV	0.456438 mV	401.7	392.1	100.00 %
7	PinPMU p40 19.e130	P	−1200 mV	−100 mV	Samples	30	0	−637.36 mV	0.522043 mV	351.2	343.1	100.00 %
8	PinPMU p41 19.e139	P	−1200 mV	−100 mV	Samples	30	0	−637.402 mV	0.548619 mV	334.2	326.5	100.00 %
9	PinPMU p42 19.e147	P	−1200 mV	−100 mV	Samples	30	0	−637.723 mV	0.336449 mV	544.9	532.7	100.00 %
10	PinPMU p43 19.e151	P	−1200 mV	−100 mV	Samples	30	0	−637.326 mV	0.477768 mV	383.7	374.9	100.00 %
11	PinPMU p50 19.e128	P	−1200 mV	−100 mV	Samples	30	0	−636.706 mV	0.453172 mV	404.6	394.8	100.00 %
12	PinPMU p51 19.g149	P	−1200 mV	−100 mV	Samples	30	0	−633.932 mV	0.267884 mV	684.4	664.4	100.00 %
13	PinPMU p52 19.e137	P	−1200 mV	−100 mV	Samples	30	0	−635.187 mV	0.546 mV	335.8	326.7	100.00 %
14	PinPMU p53 19.e135	P	−1200 mV	−100 mV	Samples	30	0	−635.339 mV	0.505918 mV	362.4	352.7	100.00 %
15	PinPMU p60 19.g130	P	−1200 mV	−100 mV	Samples	30	0	−634.869 mV	0.543932 mV	337.1	327.8	100.00 %
16	PinPMU p61 19.g104	P	−1200 mV	−100 mV	Samples	30	0	−634.964 mV	0.525765 mV	348.7	339.2	100.00 %
17	PinPMU p62 19.g102	P	−1200 mV	−100 mV	Samples	30	0	−634.991 mV	0.606408 mV	302.3	294.1	100.00 %
18	PinPMU p63 19.e102	P	−1200 mV	−100 mV	Samples	30	0	−634.948 mV	0.506749 mV	361.8	351.9	100.00 %
19	PinPMU p70 19.g139	P	−1200 mV	−100 mV	Samples	30	0	−636.913 mV	0.496847 mV	369.0	360.2	100.00 %
20	PinPMU p71 19.g147	P	−1200 mV	−100 mV	Samples	30	0	−635.359 mV	0.496418 mV	369.3	359.5	100.00 %
21	PinPMU p72 19.e104	P	−1200 mV	−100 mV	Samples	30	0	−634.919 mV	0.436613 mV	419.9	408.4	100.00 %
22	PinPMU p73 19.e108	P	−1200 mV	−100 mV	Samples	30	0	−634.746 mV	0.49972 mV	366.9	356.7	100.00 %
23	PinPMU cs 19.g106	P	−1200 mV	−100 mV	Samples	30	0	−636.079 mV	0.38799 mV	472.5	460.6	100.00 %
24	PinPMU prog 19.g124	P	−1200 mV	−100 mV	Samples	30	0	−637.019 mV	0.434235 mV	422.2	412.2	100.00 %
25	SeqLeakage1 p20 19.g128	P	−30 uA	10 uA	Samples	30	0	−0.729374 uA	0.0129481 uA	514.9	276.2	100.00 %
26	SeqLeakage1 p21 19.g126	P	−30 uA	10 uA	Samples	30	0	−0.734032 uA	0.0129127 uA	516.3	277.1	100.00 %
27	SeqLeakage1 p22 19.e126	P	−30 uA	10 uA	Samples	30	0	−0.729094 uA	0.0107395 uA	620.8	333.0	100.00 %
28	SeqLeakage1 p23 19.e124	P	−30 uA	10 uA	Samples	30	0	−0.734383 uA	0.0125859 uA	529.7	284.3	100.00 %
29	SeqLeakage2 cs 19.g106	P	−30 uA	10 uA	Samples	30	0	0.00395333 uA	0.00744495 uA	895.5	447.6	100.00 %
Test	**Name**	**Type**	**Low L.**	**High L.**	**Source**	**Execs**	**Fails**	**Mean**	**Sigma**	**Cp**	**Cpk**	**Yield**
30	SeqLeakage2 prog 19.g124	P	−30 uA	10 uA	Samples	30	0	0.00275042 uA	0.0116809 uA	570.7	285.3	100.00 %
31	VBT_outpleakage1 p40 19.e130	P	−10 uA	20 uA	Samples	30	0	0.00265608 uA	0.00870252 uA	574.5	383.1	100.00 %
32	VBT_outpleakage1 p41 19.e139	P	−10 uA	20 uA	Samples	30	0	0.00290898 uA	0.0083738 uA	597.1	398.2	100.00 %
33	VBT_outpleakage1 p42 19.e147	P	−10 uA	20 uA	Samples	30	0	0.00347528 uA	0.0129801 uA	385.2	256.9	100.00 %
34	VBT_outpleakage1 p43 19.e151	P	−10 uA	20 uA	Samples	30	0	0.00356763 uA	0.00867966 uA	576.1	384.2	100.00 %

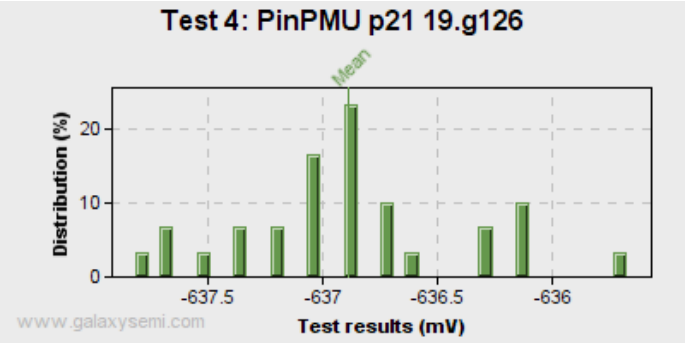
35	VBT_outpleakage1 p50 19.e128	P	−10 uA	20 uA	Samples	30	0	0.00230935 uA	0.0124362 uA	402.1	268.1	100.00 %
36	VBT_outpleakage1 p51 19.g149	P	−10 uA	20 uA	Samples	30	0	0.00553546 uA	0.010967 uA	455.9	304.1	100.00 %
37	VBT_outpleakage1 p52 19.e137	P	−10 uA	20 uA	Samples	30	0	0.00283339 uA	0.00943722 uA	529.8	353.3	100.00 %
38	VBT_outpleakage1 p53 19.e135	P	−10 uA	20 uA	Samples	30	0	−7.61717e−05 uA	0.00802581 uA	623.0	415.3	100.00 %
39	VBT_outpleakage1 p60 19.g130	P	−10 uA	20 uA	Samples	30	0	−0.000280594 uA	0.010815 uA	462.3	308.2	100.00 %
40	VBT_outpleakage1 p61 19.g104	P	−10 uA	20 uA	Samples	30	0	0.00432535 uA	0.00920875 uA	543.0	362.1	100.00 %
41	VBT_outpleakage1 p62 19.g102	P	−10 uA	20 uA	Samples	30	0	0.00520405 uA	0.0112894 uA	442.9	295.4	100.00 %
42	VBT_outpleakage1 p63 19.e102	P	−10 uA	20 uA	Samples	30	0	0.00442272 uA	0.00974089 uA	513.3	342.4	100.00 %
43	VBT_outpleakage1 p70 19.g139	P	−10 uA	20 uA	Samples	30	0	−0.000660832 uA	0.00956494 uA	522.7	348.5	100.00 %
44	VBT_outpleakage1 p71 19.g147	P	−10 uA	20 uA	Samples	30	0	0.00590493 uA	0.0109735 uA	455.6	303.9	100.00 %
45	VBT_outpleakage1 p72 19.e104	P	−10 uA	20 uA	Samples	30	0	−0.00276968 uA	0.0140168 uA	356.7	237.7	100.00 %
46	VBT_outpleakage1 p73 19.e108	P	−10 uA	20 uA	Samples	30	0	0.00467518 uA	0.0135385 uA	369.3	246.3	100.00 %
47	OutputZ_leak_vbt1 p40 19.e130	P	−10 uA	20 uA	Samples	30	0	−0.00066402 uA	0.0100879 uA	495.6	330.4	100.00 %
48	OutputZ_leak_vbt1 p41 19.e139	P	−10 uA	20 uA	Samples	30	0	0.00145449 uA	0.00848015 uA	589.6	393.1	100.00 %
49	OutputZ_leak_vbt1 p42 19.e147	P	−10 uA	20 uA	Samples	30	0	0.000608808 uA	0.00935326 uA	534.6	356.4	100.00 %
50	OutputZ_leak_vbt1 p43 19.e151	P	−10 uA	20 uA	Samples	30	0	−0.000611593 uA	0.0103138 uA	484.8	323.2	100.00 %
51	OutputZ_leak_vbt1 p50 19.e128	P	−10 uA	20 uA	Samples	30	0	−0.000329907 uA	0.00910406 uA	549.2	366.1	100.00 %
52	OutputZ_leak_vbt1 p51 19.g149	P	−10 uA	20 uA	Samples	30	0	−0.000102036 uA	0.00844955 uA	591.7	394.5	100.00 %
53	OutputZ_leak_vbt1 p52 19.e137	P	−10 uA	20 uA	Samples	30	0	−0.00321628 uA	0.00934517 uA	535.0	356.6	100.00 %
54	OutputZ_leak_vbt1 p53 19.e135	P	−10 uA	20 uA	Samples	30	0	−0.00264062 uA	0.0109924 uA	454.9	303.2	100.00 %
55	OutputZ_leak_vbt1 p60 19.g130	P	−10 uA	20 uA	Samples	30	0	−0.00204068 uA	0.00955958 uA	523.0	348.6	100.00 %
56	OutputZ_leak_vbt1 p61 19.g104	P	−10 uA	20 uA	Samples	30	0	0.00763297 uA	0.0119755 uA	417.5	278.6	100.00 %
57	OutputZ_leak_vbt1 p62 19.g102	P	−10 uA	20 uA	Samples	30	0	0.00877546 uA	0.0120145 uA	416.2	277.7	100.00 %
58	OutputZ_leak_vbt1 p63 19.e102	P	−10 uA	20 uA	Samples	30	0	−7.62538e−05 uA	0.0102121 uA	489.6	326.4	100.00 %
59	OutputZ_leak_vbt1 p70 19.g139	P	−10 uA	20 uA	Samples	30	0	−0.00289749 uA	0.00899474 uA	555.9	370.5	100.00 %
60	OutputZ_leak_vbt1 p71 19.g147	P	−10 uA	20 uA	Samples	30	0	0.000587937 uA	0.010324 uA	484.3	322.9	100.00 %
61	OutputZ_leak_vbt1 p72 19.e104	P	−10 uA	20 uA	Samples	30	0	−0.00208361 uA	0.0118905 uA	420.5	280.3	100.00 %
Test	**Name**	**Type**	**Low L.**	**High L.**	**Source**	**Execs**	**Fails**	**Mean**	**Sigma**	**Cp**	**Cpk**	**Yield**
62	OutputZ_leak_vbt1 p73 19.e108	P	−10 uA	20 uA	Samples	30	0	0.00198187 uA	0.00990863 uA	504.6	336.5	100.00 %
63	Functional_T4	F	n/a .	n/a .	Samples	30	0	n/a .	n/a .	n/a .	n/a .	100.00 %
64	icc_static_vbt11 vcc 15.e201 <> Icc_static	P	10 uA	500 uA	Samples	30	0	21.2705 uA	0.330454 uA	247.1	11.37	100.00 %
65	Icc_dynamic vcc 15.e201 <> Icc_dynamic	P	10 uA	500 uA	Samples	30	0	20.7699 uA	0.241033 uA	338.8	14.89	100.00 %
67	Functional_T5 p50 19.e128	P	n/a .	n/a .	Samples	30	0	0.144233	0.00244503	n/a .	n/a .	100.00 %
68	Functional_T5 p50 19.e128	P	n/a .	n/a .	Samples	30	0	3.28307	0.00174065	n/a .	n/a .	100.00 %
70	Functional_T6 p50 19.e128	P	150 ns	350 ns	Samples	30	0	232.933 ns	1.63861 ns	20.34	16.87	100.00 %
71	Functional_T6 p50 19.e128	P	150 ns	350 ns	Samples	30	0	244.733 ns	2.06671 ns	16.13	15.28	100.00 %
72	Functional_T6 A8 0	P	1 ns	100 ns	Samples	30	0	11.8 ns	2.53799 ns	6.50	1.42	100.00 %
73	Functional_T7 p53 19.e135	P	n/a .	n/a .	Samples	30	0	3.28297 V	0.00215735 V	n/a .	n/a .	100.00 %
74	Functional_T7 p53 19.e135	P	n/a .	n/a .	Samples	30	0	0.1387	0.00238023	n/a .	n/a .	100.00 %
78	Functional_T8 A8 0	P	1 ns	100 ns	Samples	30	5	104.067 ns	540.921 ns	0.0305	−0.0025	83.33 %
786000	Soft_Bin parameter	−	n/a .	n/a .	Samples	30	0	1	0	n/a .	n/a .	100.00 %
786001	Hard_Bin parameter	−	n/a .	n/a .	Samples	30	0	1	0	n/a .	n/a .	100.00 %
786002	Die_X parameter	−	n/a .	n/a .	Samples	30	0	2	1.43839	n/a .	n/a .	100.00 %
786003	Die_Y parameter	−	n/a .	n/a .	Samples	30	0	2.5	1.73702	n/a .	n/a .	100.00 %
786004	Test_Time parameter	−	0.0 sec	n/a .	Samples	30	0	2.16657 sec	0.061458 sec	n/a .	11.75	100.00 %
786006	Testing_Site parameter	−	n/a .	n/a .	Samples	30	0	0	0	n/a .	n/a .	100.00 %
786007	Part_ID parameter	−	n/a .	n/a .	Samples	30	0	16.5	8.80341	n/a .	n/a .	100.00 %

Histogram of Tests

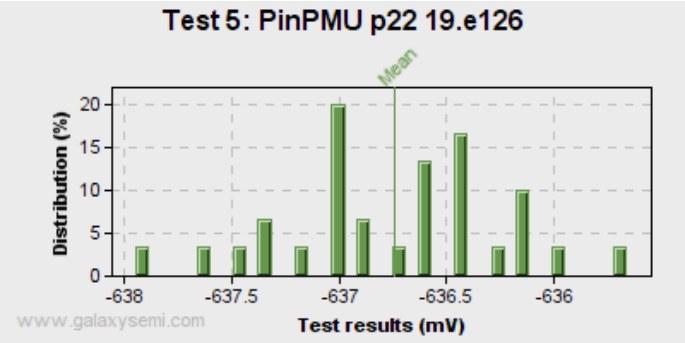
Test	3
Name	PinPMU p20 19.g128
Test type	Parametric
Low limit	−1200 mV
High limit	−100 mV
Exec / Fails	30 / 0 (0.00%)
Mean	−636.705 mV
Sigma	0.56067 mV
Range	2.13671 mV
Cp / Cpk	327.0 / 319.1
Samples	30



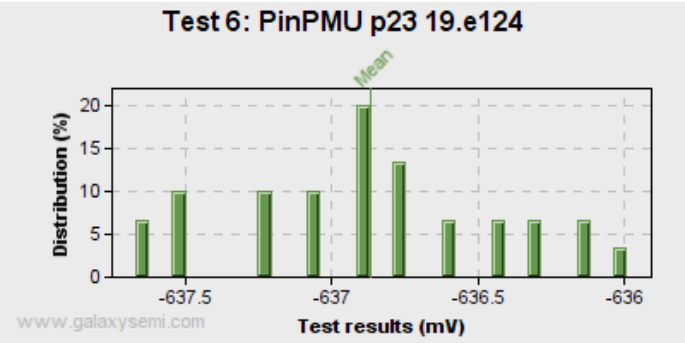
Test	4
Name	PinPMU p21 19.g126
Test type	Parametric
Low limit	−1200 mV
High limit	−100 mV
Exec / Fails	30 / 0 (0.00%)
Mean	−636.888 mV
Sigma	0.499823 mV
Range	2.13689 mV
Cp / Cpk	366.8 / 358.1
Samples	30



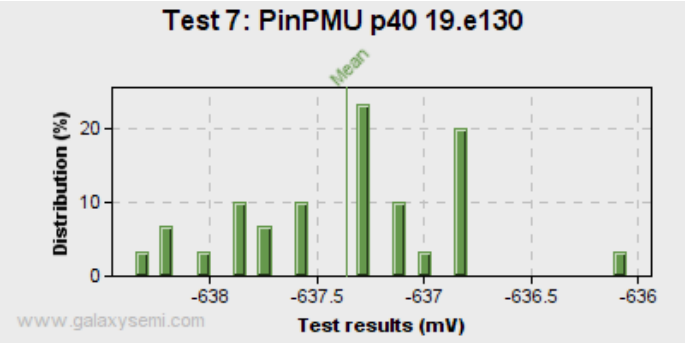
Test	5
Name	PinPMU p22 19.e126
Test type	Parametric
Low limit	−1200 mV
High limit	−100 mV
Exec / Fails	30 / 0 (0.00%)
Mean	−636.739 mV
Sigma	0.527604 mV
Range	2.28894 mV
Cp / Cpk	347.5 / 339.1
Samples	30



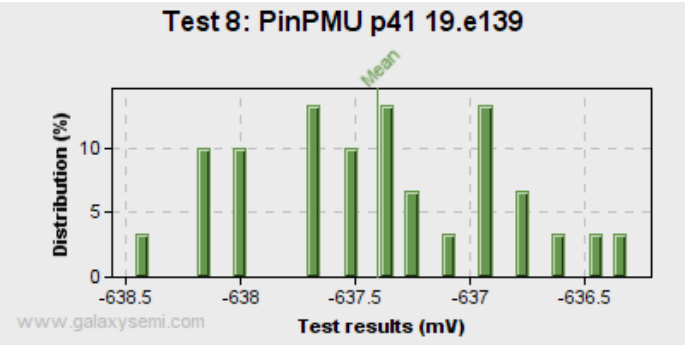
Test	6
Name	PinPMU p23 19.e124
Test type	Parametric
Low limit	−1200 mV
High limit	−100 mV
Exec / Fails	30 / 0 (0.00%)
Mean	−636.87 mV
Sigma	0.456438 mV
Range	1.67888 mV
Cp / Cpk	401.7 / 392.1
Samples	30



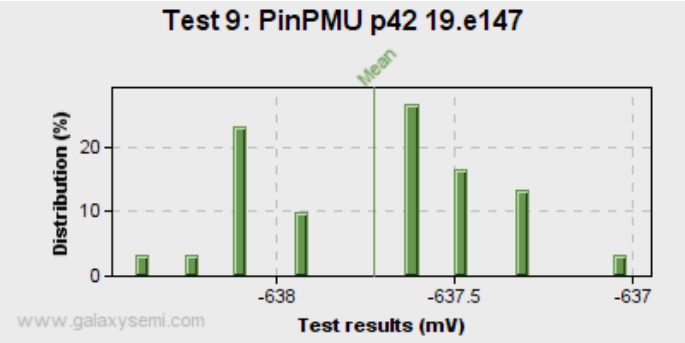
Test	7
Name	PinPMU p40 19.e130
Test type	Parametric
Low limit	−1200 mV
High limit	−100 mV
Exec / Fails	30 / 0 (0.00%)
Mean	−637.36 mV
Sigma	0.522043 mV
Range	2.28906 mV
Cp / Cpk	351.2 / 343.1
Samples	30



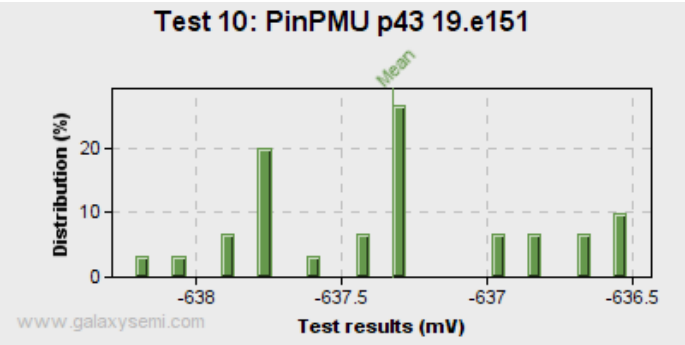
Test	8
Name	PinPMU p41 19.e139
Test type	Parametric
Low limit	−1200 mV
High limit	−100 mV
Exec / Fails	30 / 0 (0.00%)
Mean	−637.402 mV
Sigma	0.548619 mV
Range	2.13671 mV
Cp / Cpk	334.2 / 326.5
Samples	30



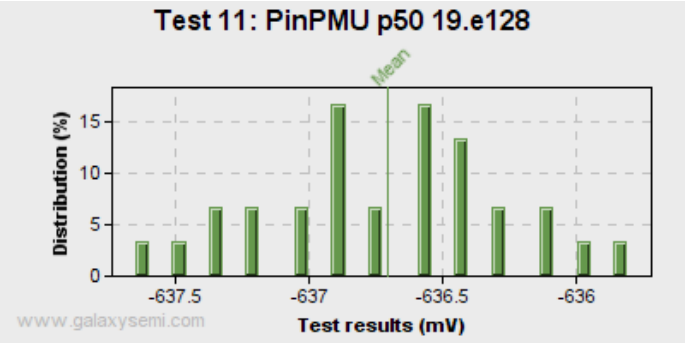
Test	9
Name	PinPMU p42 19.e147
Test type	Parametric
Low limit	−1200 mV
High limit	−100 mV
Exec / Fails	30 / 0 (0.00%)
Mean	−637.723 mV
Sigma	0.336449 mV
Range	1.37341 mV
Cp / Cpk	544.9 / 532.7
Samples	30



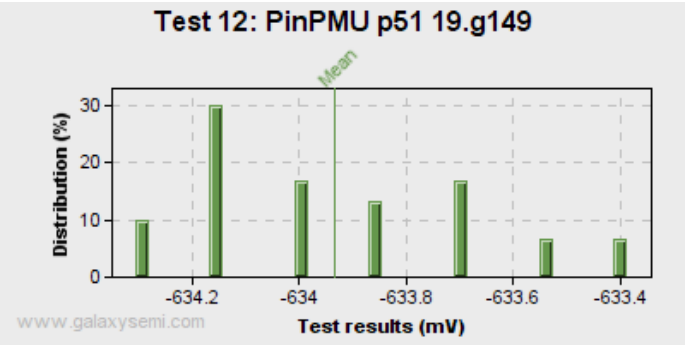
Test	10
Name	PinPMU p43 19.e151
Test type	Parametric
Low limit	−1200 mV
High limit	−100 mV
Exec / Fails	30 / 0 (0.00%)
Mean	−637.326 mV
Sigma	0.477768 mV
Range	1.67978 mV
Cp / Cpk	383.7 / 374.9
Samples	30



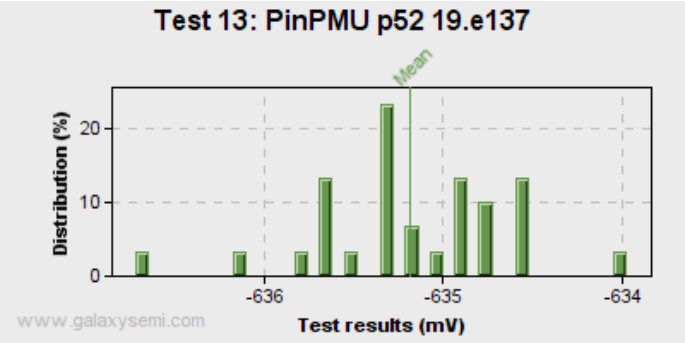
Test	11
Name	PinPMU p50 19.e128
Test type	Parametric
Low limit	−1200 mV
High limit	−100 mV
Exec / Fails	30 / 0 (0.00%)
Mean	−636.706 mV
Sigma	0.453172 mV
Range	1.83219 mV
Cp / Cpk	404.6 / 394.8
Samples	30



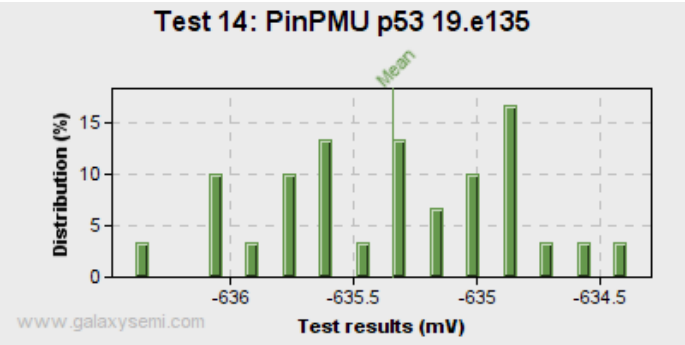
Test	12
Name	PinPMU p51 19.g149
Test type	Parametric
Low limit	−1200 mV
High limit	−100 mV
Exec / Fails	30 / 0 (0.00%)
Mean	−633.932 mV
Sigma	0.267884 mV
Range	0.915587 mV
Cp / Cpk	684.4 / 664.4
Samples	30



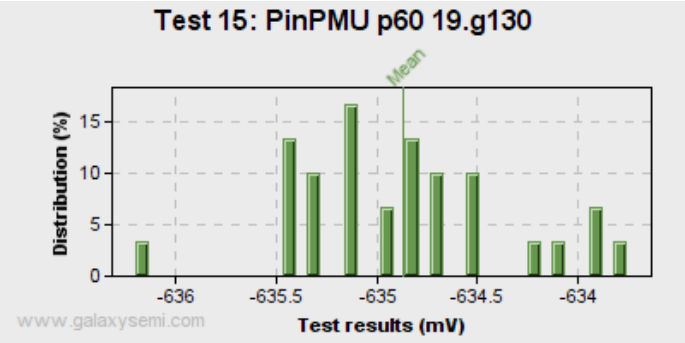
Test	13
Name	PinPMU p52 19.e137
Test type	Parametric
Low limit	−1200 mV
High limit	−100 mV
Exec / Fails	30 / 0 (0.00%)
Mean	−635.187 mV
Sigma	0.546 mV
Range	2.74789 mV
Cp / Cpk	335.8 / 326.7
Samples	30



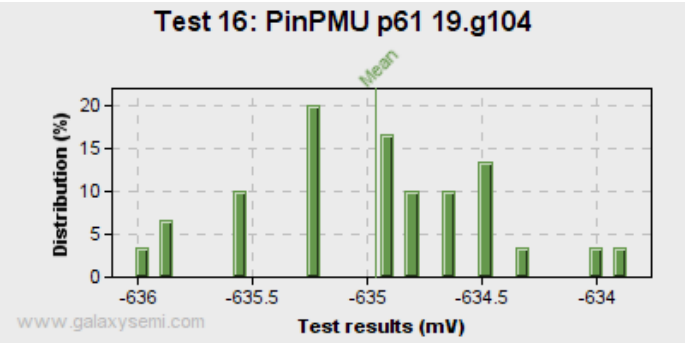
Test	14
Name	PinPMU p53 19.e135
Test type	Parametric
Low limit	−1200 mV
High limit	−100 mV
Exec / Fails	30 / 0 (0.00%)
Mean	−635.339 mV
Sigma	0.505918 mV
Range	1.98364 mV
Cp / Cpk	362.4 / 352.7
Samples	30



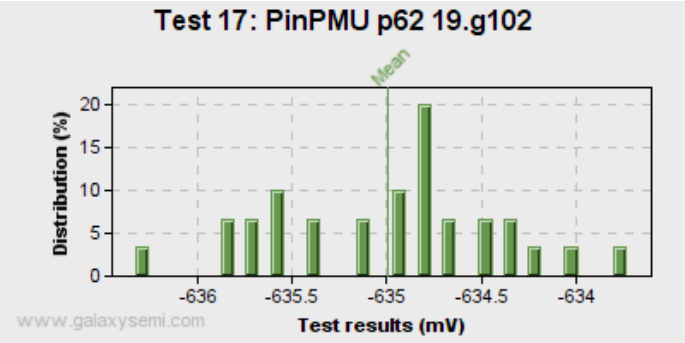
Test	15
Name	PinPMU p60 19.g130
Test type	Parametric
Low limit	−1200 mV
High limit	−100 mV
Exec / Fails	30 / 0 (0.00%)
Mean	−634.869 mV
Sigma	0.543932 mV
Range	2.44212 mV
Cp / Cpk	337.1 / 327.8
Samples	30



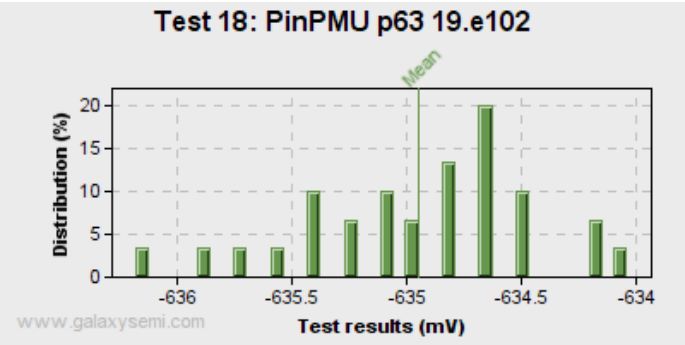
Test	16
Name	PinPMU p61 19.g104
Test type	Parametric
Low limit	−1200 mV
High limit	−100 mV
Exec / Fails	30 / 0 (0.00%)
Mean	−634.964 mV
Sigma	0.525765 mV
Range	2.13665 mV
Cp / Cpk	348.7 / 339.2
Samples	30



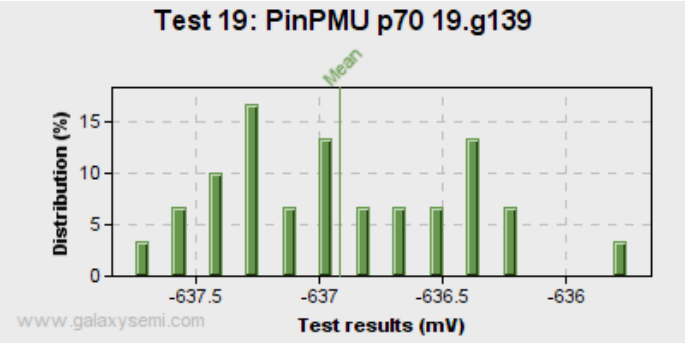
Test	17
Name	PinPMU p62 19.g102
Test type	Parametric
Low limit	−1200 mV
High limit	−100 mV
Exec / Fails	30 / 0 (0.00%)
Mean	−634.991 mV
Sigma	0.606408 mV
Range	2.59441 mV
Cp / Cpk	302.3 / 294.1
Samples	30



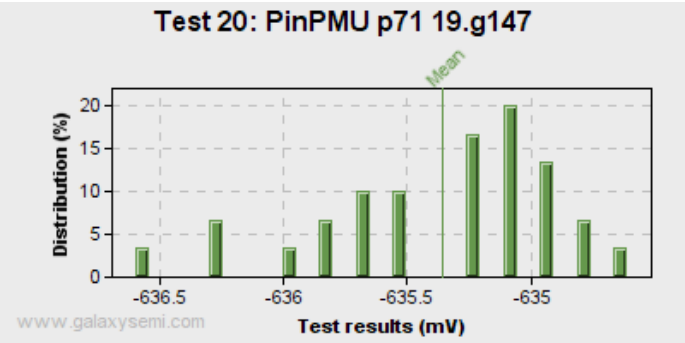
Test	18
Name	PinPMU p63 19.e102
Test type	Parametric
Low limit	−1200 mV
High limit	−100 mV
Exec / Fails	30 / 0 (0.00%)
Mean	−634.948 mV
Sigma	0.506749 mV
Range	2.13617 mV
Cp / Cpk	361.8 / 351.9
Samples	30



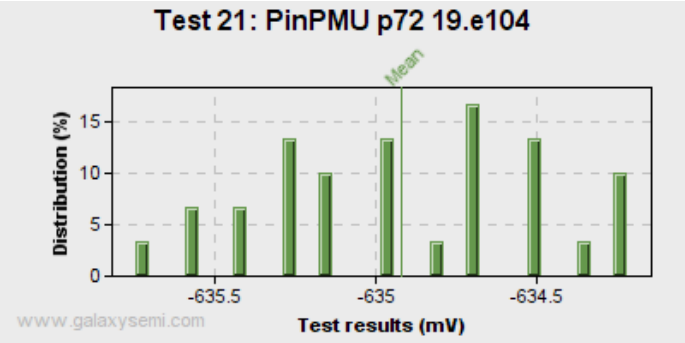
Test	19
Name	PinPMU p70 19.g139
Test type	Parametric
Low limit	−1200 mV
High limit	−100 mV
Exec / Fails	30 / 0 (0.00%)
Mean	−636.913 mV
Sigma	0.496847 mV
Range	1.98448 mV
Cp / Cpk	369.0 / 360.2
Samples	30



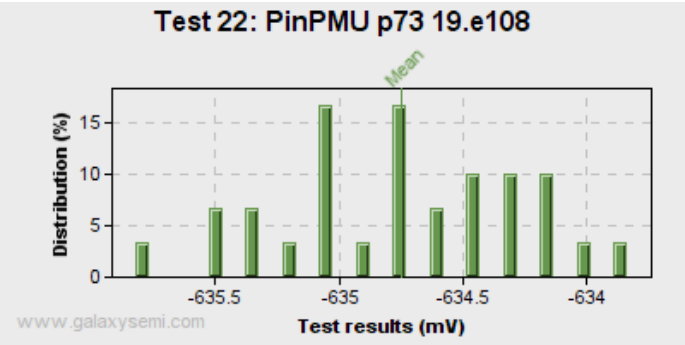
Test	20
Name	PinPMU p71 19.g147
Test type	Parametric
Low limit	−1200 mV
High limit	−100 mV
Exec / Fails	30 / 0 (0.00%)
Mean	−635.359 mV
Sigma	0.496418 mV
Range	1.98442 mV
Cp / Cpk	369.3 / 359.5
Samples	30



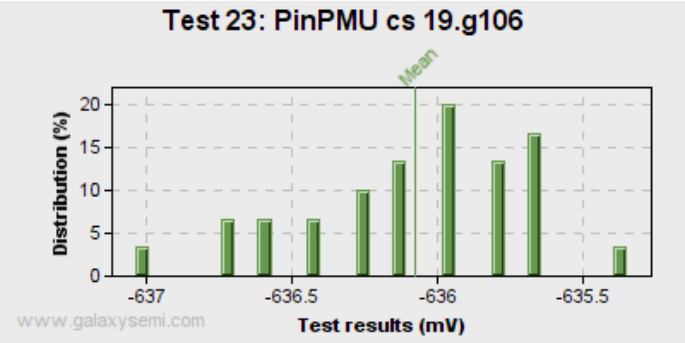
Test	21
Name	PinPMU p72 19.e104
Test type	Parametric
Low limit	−1200 mV
High limit	−100 mV
Exec / Fails	30 / 0 (0.00%)
Mean	−634.919 mV
Sigma	0.436613 mV
Range	1.52665 mV
Cp / Cpk	419.9 / 408.4
Samples	30



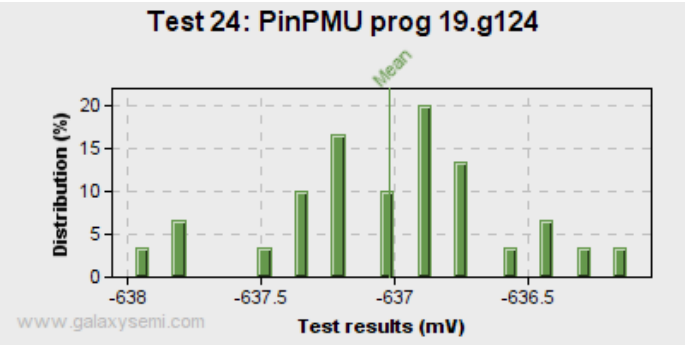
Test	22
Name	PinPMU p73 19.e108
Test type	Parametric
Low limit	−1200 mV
High limit	−100 mV
Exec / Fails	30 / 0 (0.00%)
Mean	−634.746 mV
Sigma	0.49972 mV
Range	1.98388 mV
Cp / Cpk	366.9 / 356.7
Samples	30



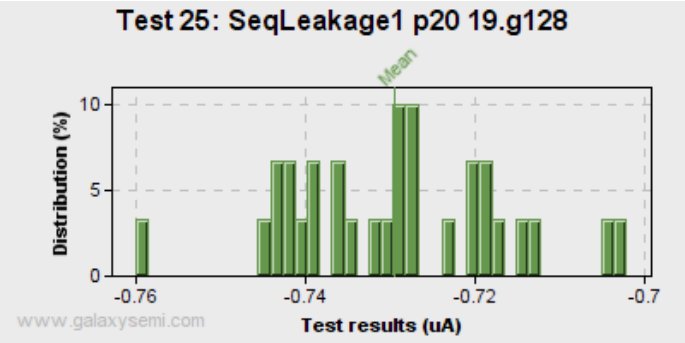
Test	23
Name	PinPMU cs 19.g106
Test type	Parametric
Low limit	−1200 mV
High limit	−100 mV
Exec / Fails	30 / 0 (0.00%)
Mean	−636.079 mV
Sigma	0.38799 mV
Range	1.67906 mV
Cp / Cpk	472.5 / 460.6
Samples	30



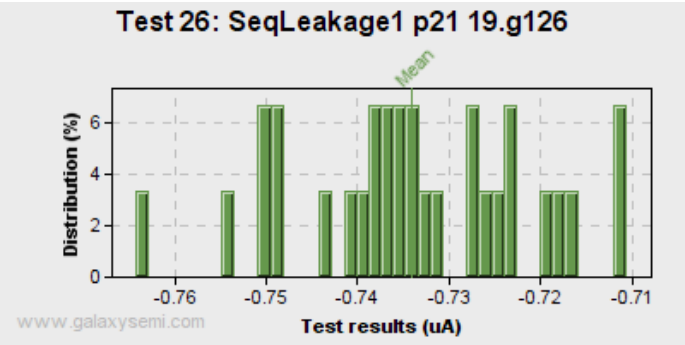
Test	24
Name	PinPMU prog 19.g124
Test type	Parametric
Low limit	−1200 mV
High limit	−100 mV
Exec / Fails	30 / 0 (0.00%)
Mean	−637.019 mV
Sigma	0.434235 mV
Range	1.83129 mV
Cp / Cpk	422.2 / 412.2
Samples	30



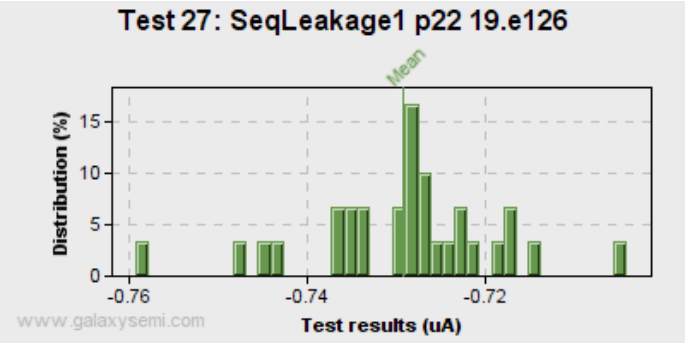
Test	25
Name	SeqLeakage1 p20 19.g128
Test type	Parametric
Low limit	–30 uA
High limit	10 uA
Exec / Fails	30 / 0 (0.00%)
Mean	–0.729374 uA
Sigma	0.0129481 uA
Range	0.0579352 uA
Cp / Cpk	514.9 / 276.2
Samples	30



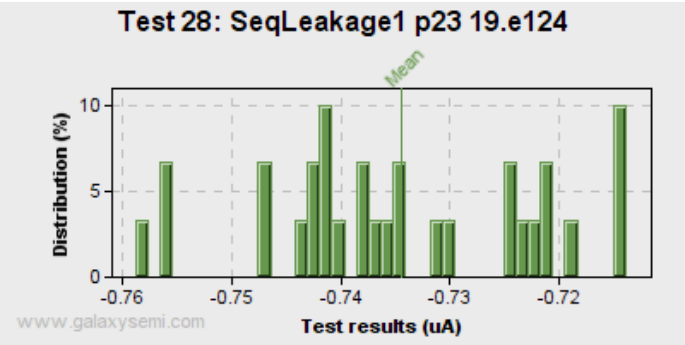
Test	26
Name	SeqLeakage1 p21 19.g126
Test type	Parametric
Low limit	–30 uA
High limit	10 uA
Exec / Fails	30 / 0 (0.00%)
Mean	–0.734032 uA
Sigma	0.0129127 uA
Range	0.0535939 uA
Cp / Cpk	516.3 / 277.1
Samples	30



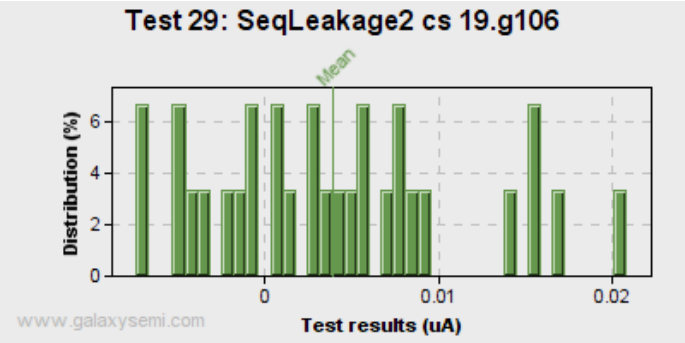
Test	27
Name	SeqLeakage1 p22 19.e126
Test type	Parametric
Low limit	–30 uA
High limit	10 uA
Exec / Fails	30 / 0 (0.00%)
Mean	–0.729094 uA
Sigma	0.0107395 uA
Range	0.0551088 uA
Cp / Cpk	620.8 / 333.0
Samples	30



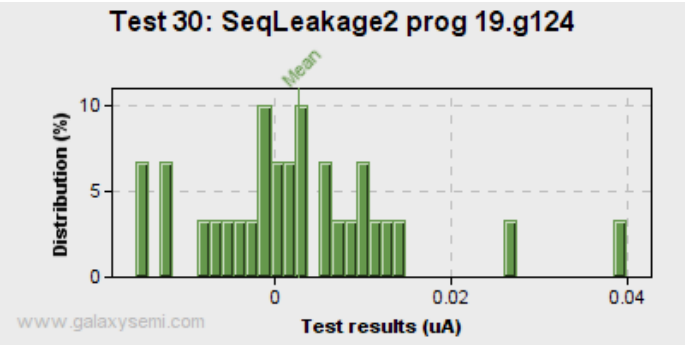
Test	28
Name	SeqLeakage1 p23 19.e124
Test type	Parametric
Low limit	–30 uA
High limit	10 uA
Exec / Fails	30 / 0 (0.00%)
Mean	–0.734383 uA
Sigma	0.0125859 uA
Range	0.0450137 uA
Cp / Cpk	529.7 / 284.3
Samples	30



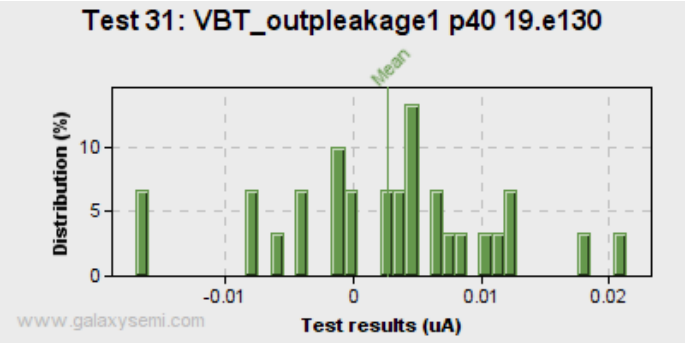
Test	29
Name	SeqLeakage2 cs 19.g106
Test type	Parametric
Low limit	−30 uA
High limit	10 uA
Exec / Fails	30 / 0 (0.00%)
Mean	0.00395333 uA
Sigma	0.00744495 uA
Range	0.028311 uA
Cp / Cpk	895.5 / 447.6
Samples	30



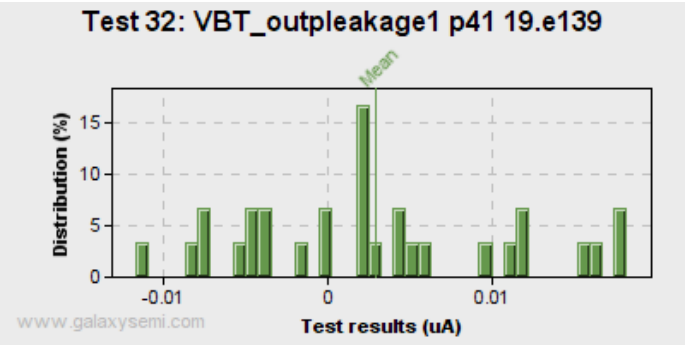
Test	30
Name	SeqLeakage2 prog 19.g124
Test type	Parametric
Low limit	−30 uA
High limit	10 uA
Exec / Fails	30 / 0 (0.00%)
Mean	0.00275042 uA
Sigma	0.0116809 uA
Range	0.0557725 uA
Cp / Cpk	570.7 / 285.3
Samples	30



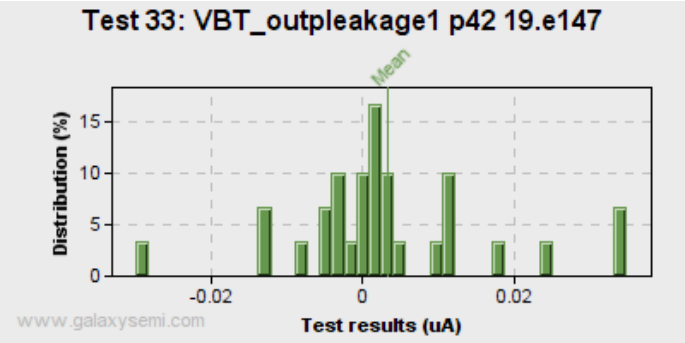
Test	31
Name	VBT_outpleakage1 p40 19.e130
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	30 / 0 (0.00%)
Mean	0.00265608 uA
Sigma	0.00870252 uA
Range	0.0383088 uA
Cp / Cpk	574.5 / 383.1
Samples	30



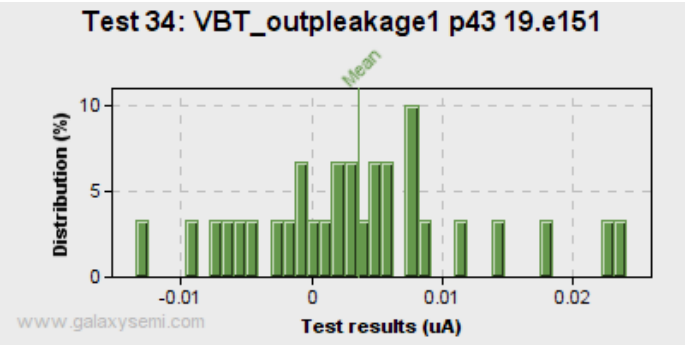
Test	32
Name	VBT_outpleakage1 p41 19.e139
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	30 / 0 (0.00%)
Mean	0.00290898 uA
Sigma	0.0083738 uA
Range	0.0298553 uA
Cp / Cpk	597.1 / 398.2
Samples	30



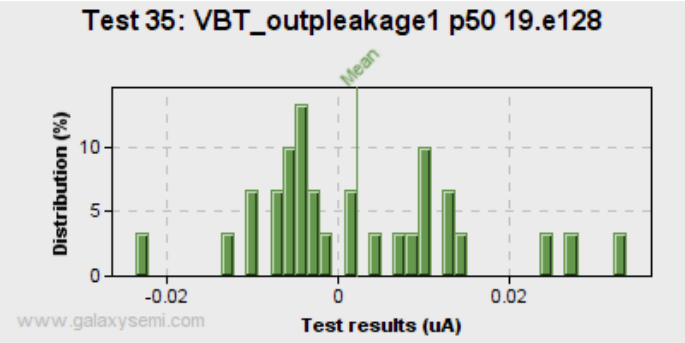
Test	33
Name	VBT_outpleakage1 p42 19.e147
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	30 / 0 (0.00%)
Mean	0.00347528 uA
Sigma	0.0129801 uA
Range	0.0646858 uA
Cp / Cpk	385.2 / 256.9
Samples	30



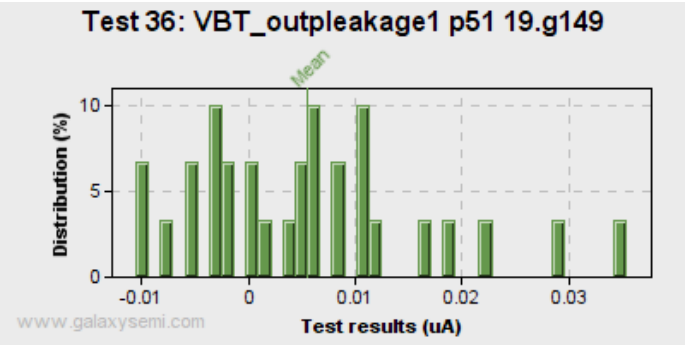
Test	34
Name	VBT_outpleakage1 p43 19.e151
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	30 / 0 (0.00%)
Mean	0.00356763 uA
Sigma	0.00867966 uA
Range	0.0374601 uA
Cp / Cpk	576.1 / 384.2
Samples	30



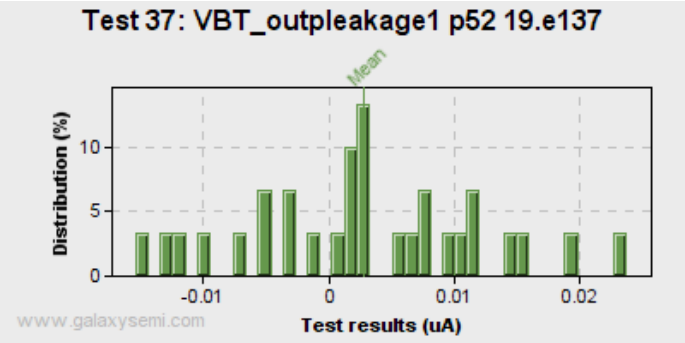
Test	35
Name	VBT_outpleakage1 p50 19.e128
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	30 / 0 (0.00%)
Mean	0.00230935 uA
Sigma	0.0124362 uA
Range	0.0570992 uA
Cp / Cpk	402.1 / 268.1
Samples	30



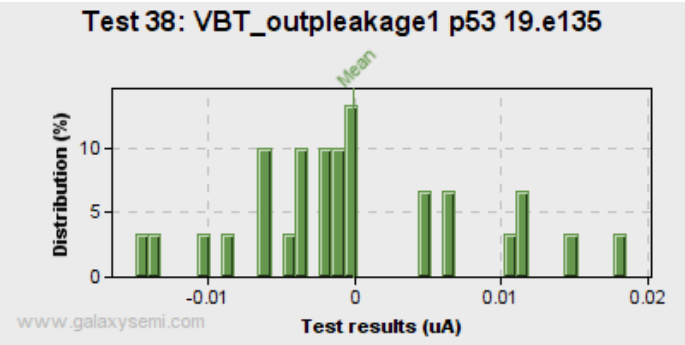
Test	36
Name	VBT_outpleakage1 p51 19.g149
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	30 / 0 (0.00%)
Mean	0.00553546 uA
Sigma	0.010967 uA
Range	0.0459163 uA
Cp / Cpk	455.9 / 304.1
Samples	30



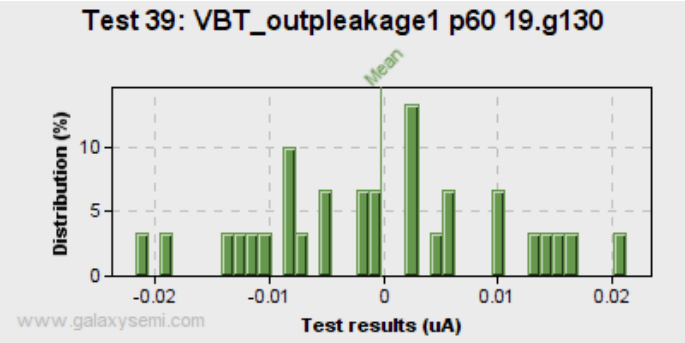
Test	37
Name	VBT_outpleakage1 p52 19.e137
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	30 / 0 (0.00%)
Mean	0.00283339 uA
Sigma	0.00943722 uA
Range	0.0390548 uA
Cp / Cpk	529.8 / 353.3
Samples	30



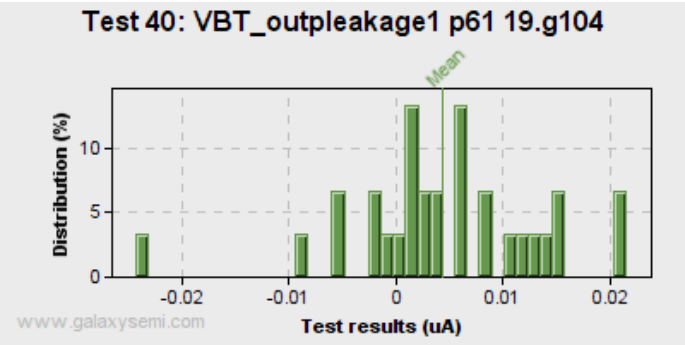
Test	38
Name	VBT_outpleakage1 p53 19.e135
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	30 / 0 (0.00%)
Mean	−7.61717e−05 uA
Sigma	0.00802581 uA
Range	0.0335155 uA
Cp / Cpk	623.0 / 415.3
Samples	30



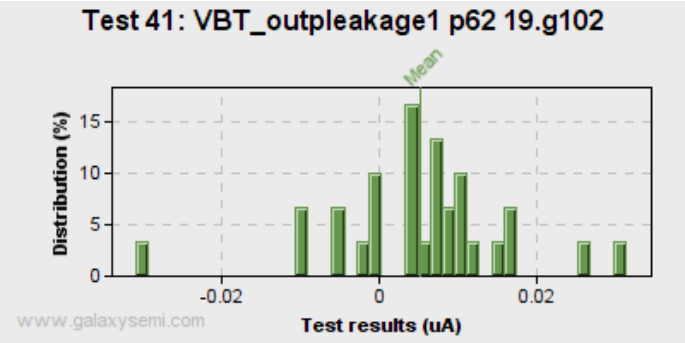
Test	39
Name	VBT_outpleakage1 p60 19.g130
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	30 / 0 (0.00%)
Mean	−0.000280594 uA
Sigma	0.010815 uA
Range	0.0428543 uA
Cp / Cpk	462.3 / 308.2
Samples	30



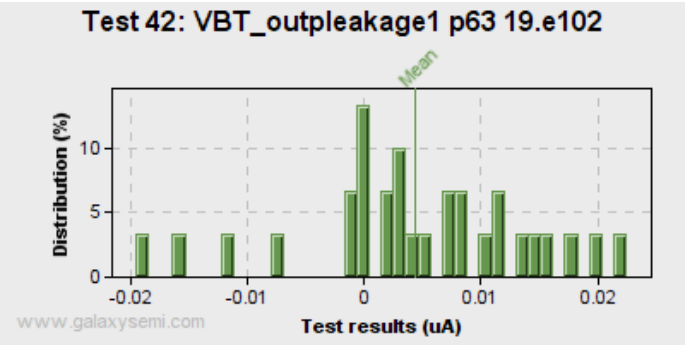
Test	40
Name	VBT_outpleakage1 p61 19.g104
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	30 / 0 (0.00%)
Mean	0.00432535 uA
Sigma	0.00920875 uA
Range	0.0457978 uA
Cp / Cpk	543.0 / 362.1
Samples	30



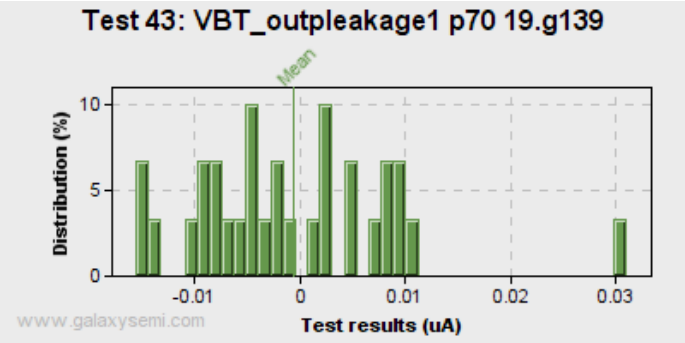
Test	41
Name	VBT_outpleakage1 p62 19.g102
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	30 / 0 (0.00%)
Mean	0.00520405 uA
Sigma	0.0112894 uA
Range	0.0619894 uA
Cp / Cpk	442.9 / 295.4
Samples	30



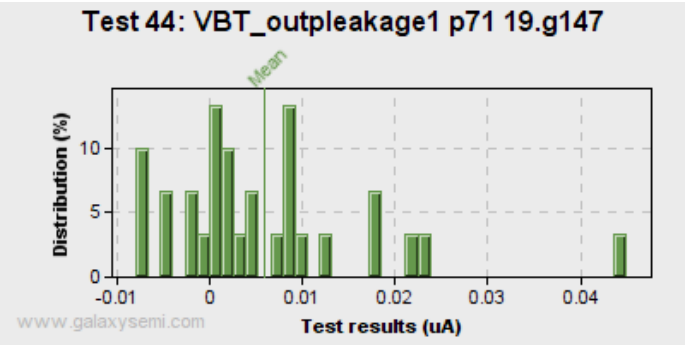
Test	42
Name	VBT_outpleakage1 p63 19.e102
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	30 / 0 (0.00%)
Mean	0.00442272 uA
Sigma	0.00974089 uA
Range	0.0419396 uA
Cp / Cpk	513.3 / 342.4
Samples	30



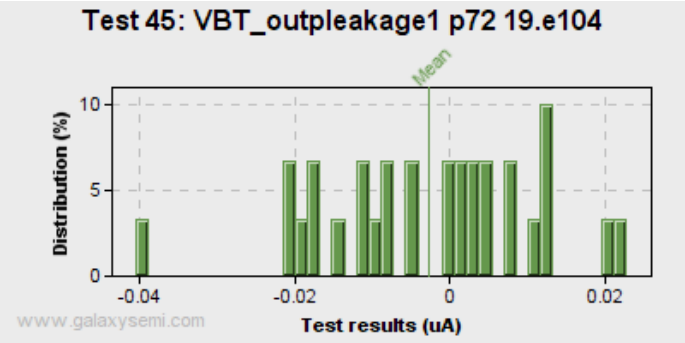
Test	43
Name	VBT_outpleakage1 p70 19.g139
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	30 / 0 (0.00%)
Mean	−0.000660832 uA
Sigma	0.00956494 uA
Range	0.0465124 uA
Cp / Cpk	522.7 / 348.5
Samples	30



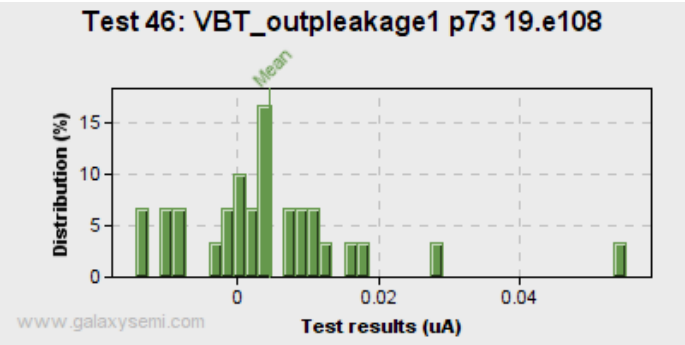
Test	44
Name	VBT_outpleakage1 p71 19.g147
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	30 / 0 (0.00%)
Mean	0.00590493 uA
Sigma	0.0109735 uA
Range	0.0529143 uA
Cp / Cpk	455.6 / 303.9
Samples	30



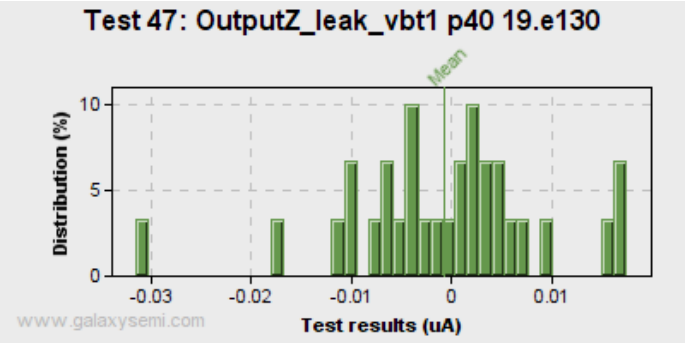
Test	45
Name	VBT_outpleakage1 p72 19.e104
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	30 / 0 (0.00%)
Mean	−0.00276968 uA
Sigma	0.0140168 uA
Range	0.0632707 uA
Cp / Cpk	356.7 / 237.7
Samples	30



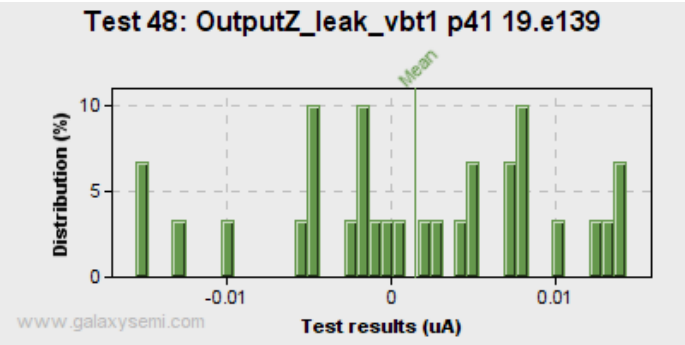
Test	46
Name	VBT_outpleakage1 p73 19.e108
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	30 / 0 (0.00%)
Mean	0.00467518 uA
Sigma	0.0135385 uA
Range	0.0693654 uA
Cp / Cpk	369.3 / 246.3
Samples	30



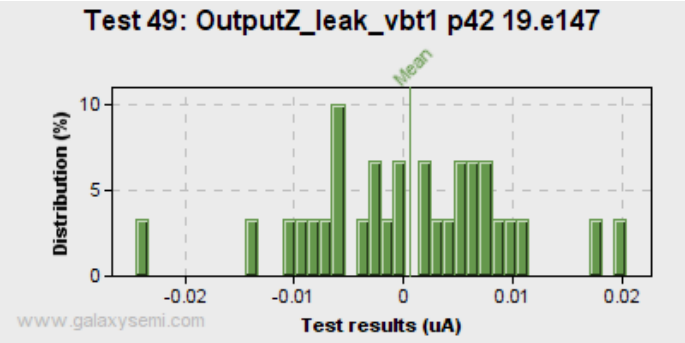
Test	47
Name	OutputZ_leak_vbt1 p40 19.e130
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	30 / 0 (0.00%)
Mean	−0.00066402 uA
Sigma	0.0100879 uA
Range	0.0490353 uA
Cp / Cpk	495.6 / 330.4
Samples	30



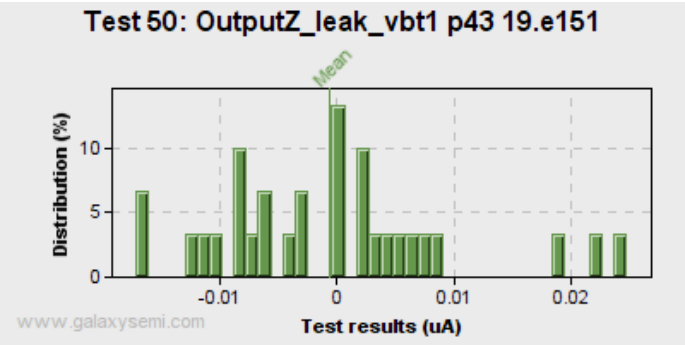
Test	48
Name	OutputZ_leak_vbt1 p41 19.e139
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	30 / 0 (0.00%)
Mean	0.00145449 uA
Sigma	0.00848015 uA
Range	0.0298553 uA
Cp / Cpk	589.6 / 393.1
Samples	30



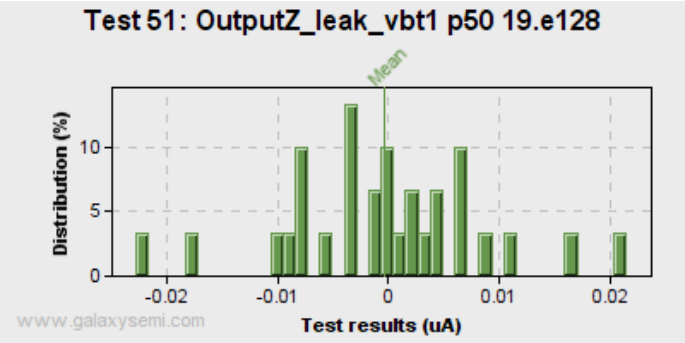
Test	49
Name	OutputZ_leak_vbt1 p42 19.e147
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	30 / 0 (0.00%)
Mean	0.000608808 uA
Sigma	0.00935326 uA
Range	0.0448996 uA
Cp / Cpk	534.6 / 356.4
Samples	30



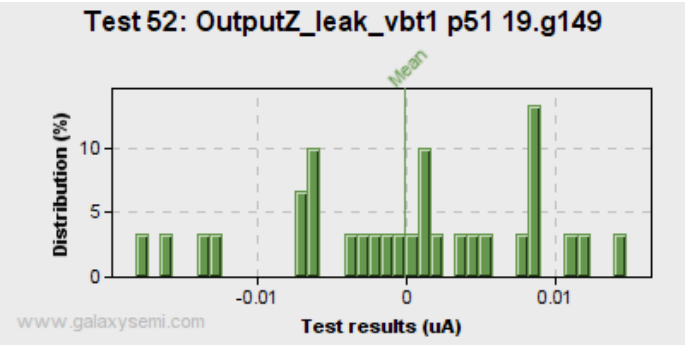
Test	50
Name	OutputZ_leak_vbt1 p43 19.e151
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	30 / 0 (0.00%)
Mean	−0.000611593 uA
Sigma	0.0103138 uA
Range	0.042047 uA
Cp / Cpk	484.8 / 323.2
Samples	30



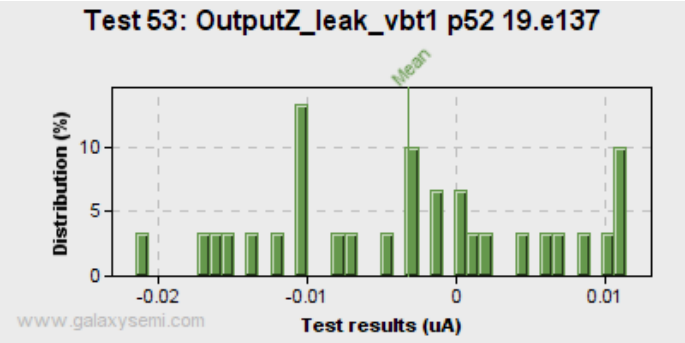
Test	51
Name	OutputZ_leak_vbt1 p50 19.e128
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	30 / 0 (0.00%)
Mean	−0.000329907 uA
Sigma	0.00910406 uA
Range	0.0441567 uA
Cp / Cpk	549.2 / 366.1
Samples	30



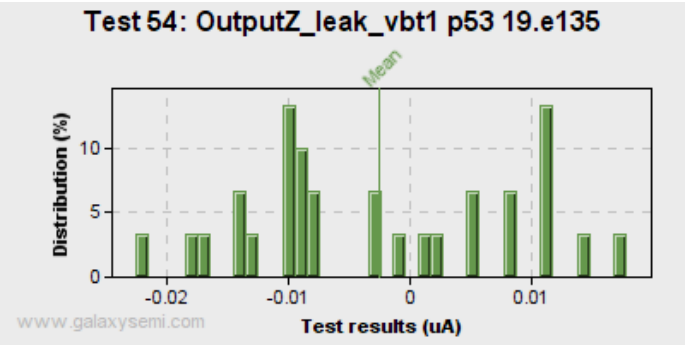
Test	52
Name	OutputZ_leak_vbt1 p51 19.g149
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	30 / 0 (0.00%)
Mean	−0.000102036 uA
Sigma	0.00844955 uA
Range	0.0329066 uA
Cp / Cpk	591.7 / 394.5
Samples	30



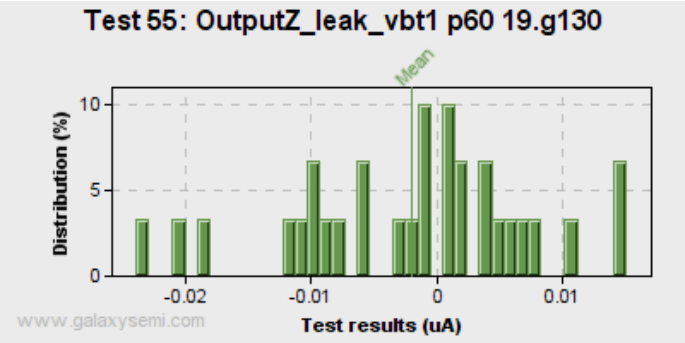
Test	53
Name	OutputZ_leak_vbt1 p52 19.e137
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	30 / 0 (0.00%)
Mean	−0.00321628 uA
Sigma	0.00934517 uA
Range	0.0329286 uA
Cp / Cpk	535.0 / 356.6
Samples	30



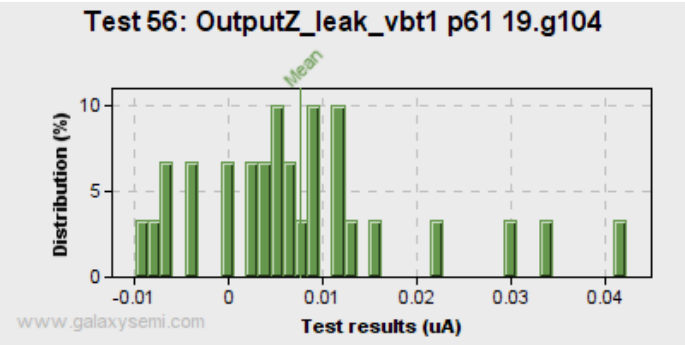
Test	54
Name	OutputZ_leak_vbt1 p53 19.e135
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	30 / 0 (0.00%)
Mean	−0.00264062 uA
Sigma	0.0109924 uA
Range	0.040371 uA
Cp / Cpk	454.9 / 303.2
Samples	30



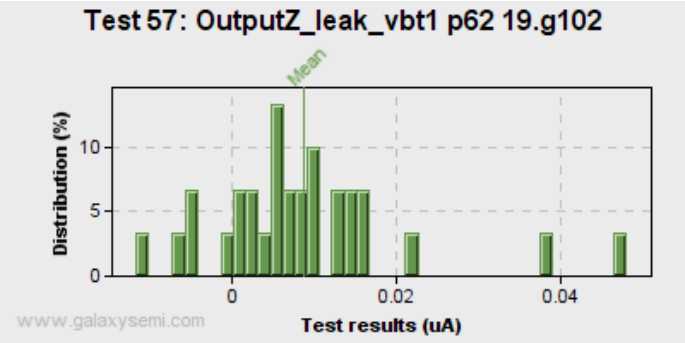
Test	55
Name	OutputZ_leak_vbt1 p60 19.g130
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	30 / 0 (0.00%)
Mean	−0.00204068 uA
Sigma	0.00955958 uA
Range	0.039028 uA
Cp / Cpk	523.0 / 348.6
Samples	30



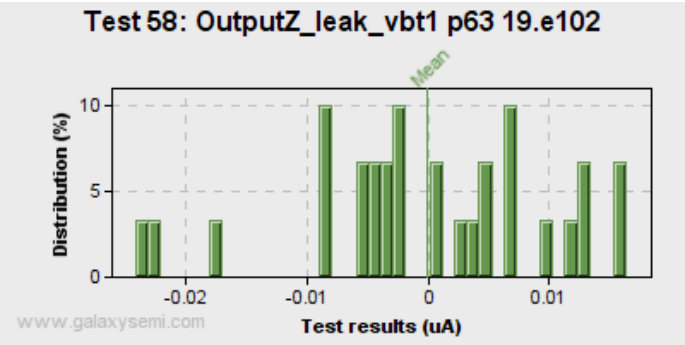
Test	56
Name	OutputZ_leak_vbt1 p61 19.g104
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	30 / 0 (0.00%)
Mean	0.00763297 uA
Sigma	0.0119755 uA
Range	0.0519042 uA
Cp / Cpk	417.5 / 278.6
Samples	30



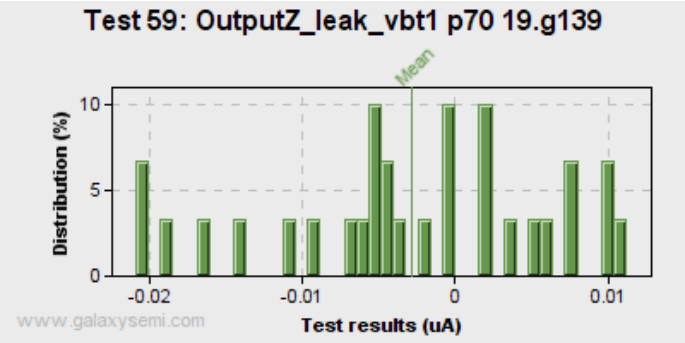
Test	57
Name	OutputZ_leak_vbt1 p62 19.g102
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	30 / 0 (0.00%)
Mean	0.00877546 uA
Sigma	0.0120145 uA
Range	0.0596935 uA
Cp / Cpk	416.2 / 277.7
Samples	30



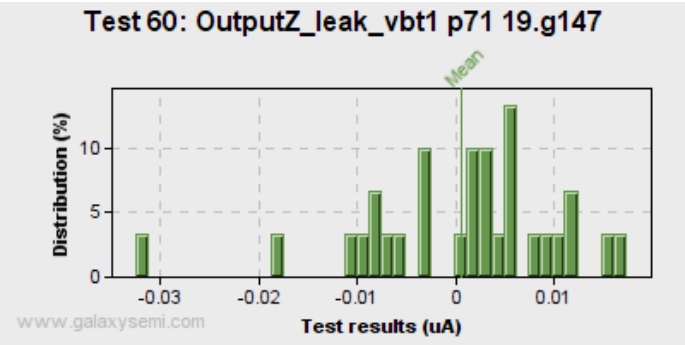
Test	58
Name	OutputZ_leak_vbt1 p63 19.e102
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	30 / 0 (0.00%)
Mean	−7.62538e−05 uA
Sigma	0.0102121 uA
Range	0.0404145 uA
Cp / Cpk	489.6 / 326.4
Samples	30



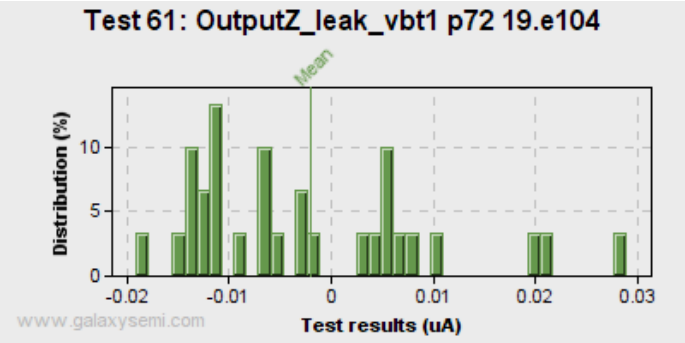
Test	59
Name	OutputZ_leak_vbt1 p70 19.g139
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	30 / 0 (0.00%)
Mean	−0.00289749 uA
Sigma	0.00899474 uA
Range	0.0320249 uA
Cp / Cpk	555.9 / 370.5
Samples	30



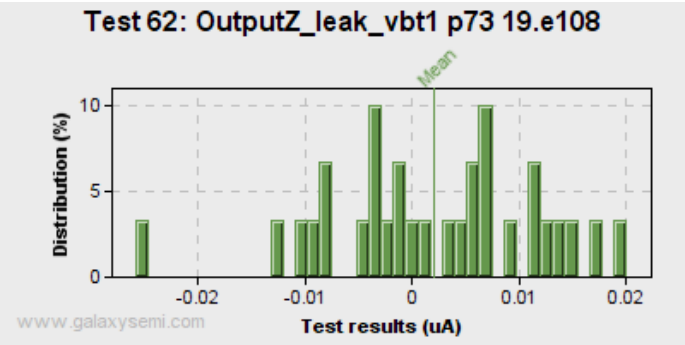
Test	60
Name	OutputZ_leak_vbt1 p71 19.g147
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	30 / 0 (0.00%)
Mean	0.000587937 uA
Sigma	0.010324 uA
Range	0.0498468 uA
Cp / Cpk	484.3 / 322.9
Samples	30



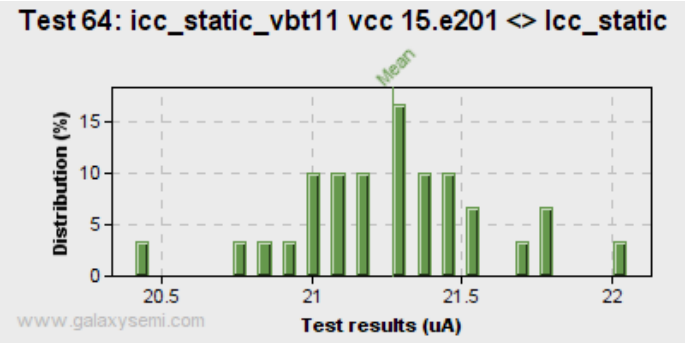
Test	61
Name	OutputZ_leak_vbt1 p72 19.e104
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	30 / 0 (0.00%)
Mean	−0.00208361 uA
Sigma	0.0118905 uA
Range	0.0480248 uA
Cp / Cpk	420.5 / 280.3
Samples	30



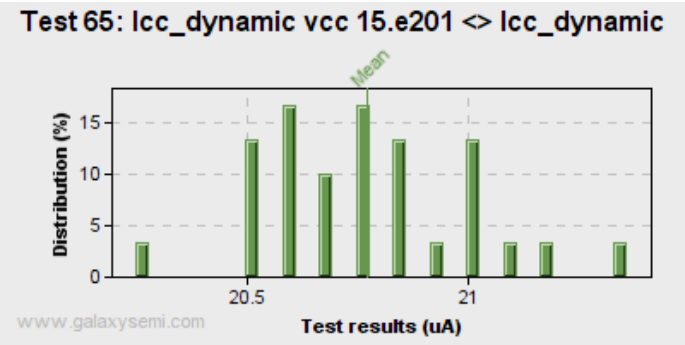
Test	62
Name	OutputZ_leak_vbt1 p73 19.e108
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	30 / 0 (0.00%)
Mean	0.00198187 uA
Sigma	0.00990863 uA
Range	0.0457354 uA
Cp / Cpk	504.6 / 336.5
Samples	30



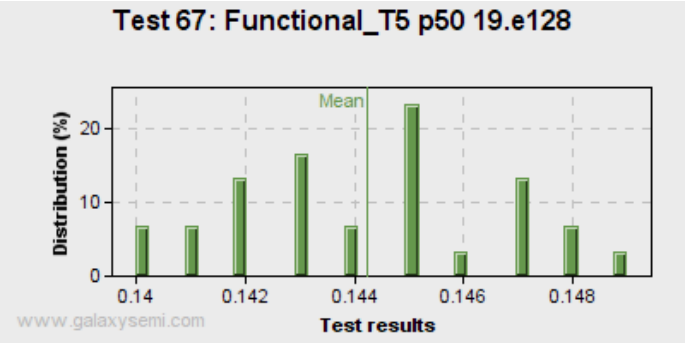
Test	64
Name	icc_static_vbt11 vcc 15.e201 <> Icc_static
Test type	Parametric
Low limit	10 uA
High limit	500 uA
Exec / Fails	30 / 0 (0.00%)
Mean	21.2705 uA
Sigma	0.330454 uA
Range	1.63078 uA
Cp / Cpk	247.1 / 11.37
Samples	30



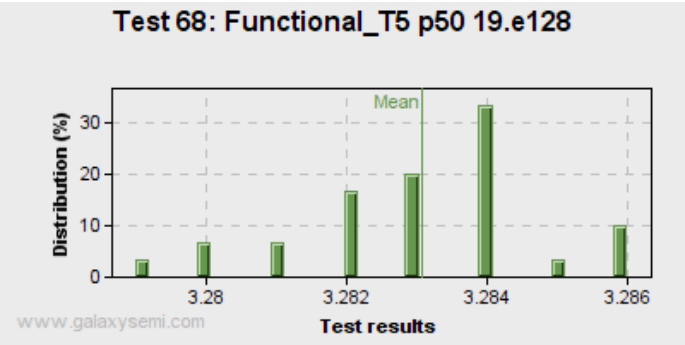
Test	65
Name	Icc_dynamic vcc 15.e201 <> Icc_dynamic
Test type	Parametric
Low limit	10 uA
High limit	500 uA
Exec / Fails	30 / 0 (0.00%)
Mean	20.7699 uA
Sigma	0.241033 uA
Range	1.1158 uA
Cp / Cpk	338.8 / 14.89
Samples	30



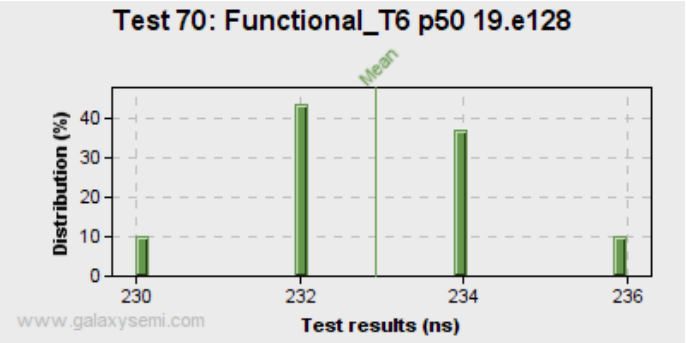
Test	67
Name	Functional_T5 p50 19.e128
Test type	Parametric
Low limit	n/a .
High limit	n/a .
Exec / Fails	30 / 0 (0.00%)
Mean	0.144233
Sigma	0.00244503
Range	0.009
Cp / Cpk	n/a . / n/a .
Samples	30



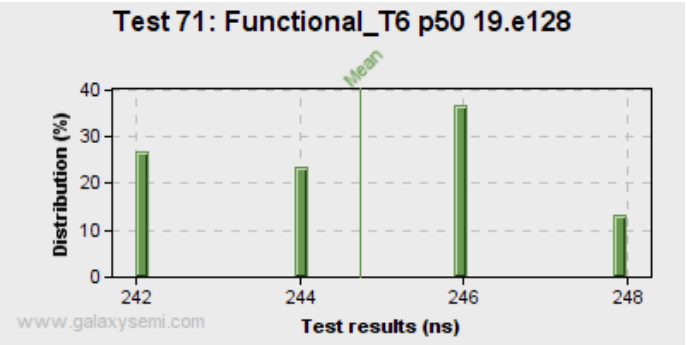
Test	68
Name	Functional_T5 p50 19.e128
Test type	Parametric
Low limit	n/a .
High limit	n/a .
Exec / Fails	30 / 0 (0.00%)
Mean	3.28307
Sigma	0.00174065
Range	0.00699997
Cp / Cpk	n/a . / n/a .
Samples	30



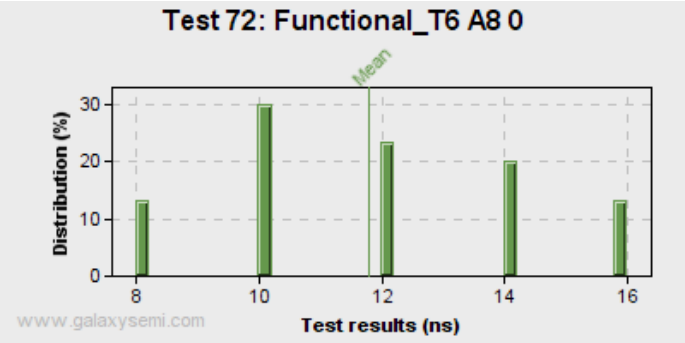
Test	70
Name	Functional_T6 p50 19.e128
Test type	Parametric
Low limit	150 ns
High limit	350 ns
Exec / Fails	30 / 0 (0.00%)
Mean	232.933 ns
Sigma	1.63861 ns
Range	6.00001 ns
Cp / Cpk	20.34 / 16.87
Samples	30



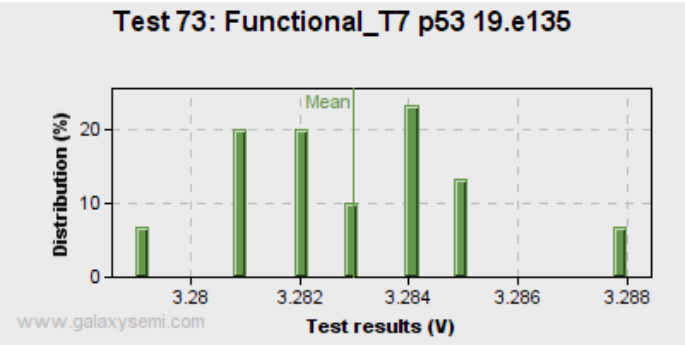
Test	71
Name	Functional_T6 p50 19.e128
Test type	Parametric
Low limit	150 ns
High limit	350 ns
Exec / Fails	30 / 0 (0.00%)
Mean	244.733 ns
Sigma	2.06671 ns
Range	5.99999 ns
Cp / Cpk	16.13 / 15.28
Samples	30



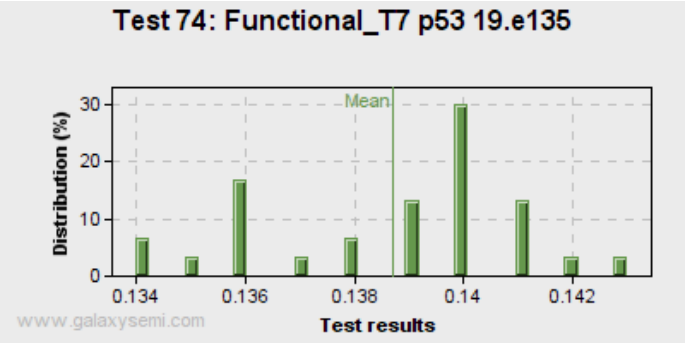
Test	72
Name	Functional_T6 A8 0
Test type	Parametric
Low limit	1 ns
High limit	100 ns
Exec / Fails	30 / 0 (0.00%)
Mean	11.8 ns
Sigma	2.53799 ns
Range	8 ns
Cp / Cpk	6.50 / 1.42
Samples	30



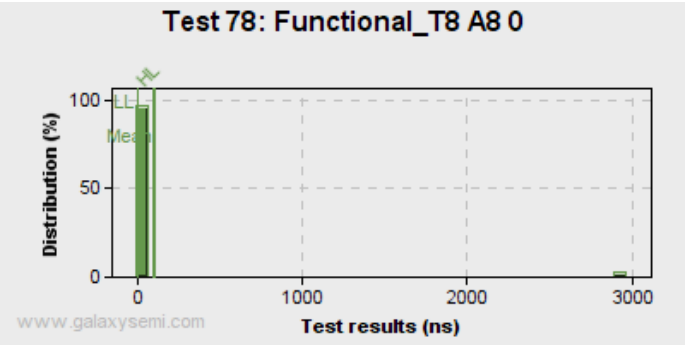
Test	73
Name	Functional_T7 p53 19.e135
Test type	Parametric
Low limit	n/a .
High limit	n/a .
Exec / Fails	30 / 0 (0.00%)
Mean	3.28297 V
Sigma	0.00215735 V
Range	0.00900006 V
Cp / Cpk	n/a . / n/a .
Samples	30



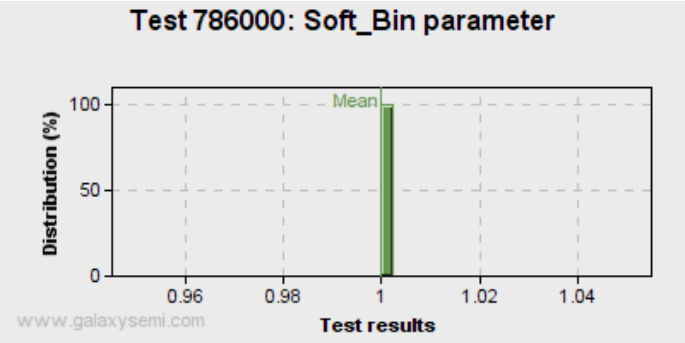
Test	74
Name	Functional_T7 p53 19.e135
Test type	Parametric
Low limit	n/a .
High limit	n/a .
Exec / Fails	30 / 0 (0.00%)
Mean	0.1387
Sigma	0.00238023
Range	0.009
Cp / Cpk	n/a . / n/a .
Samples	30



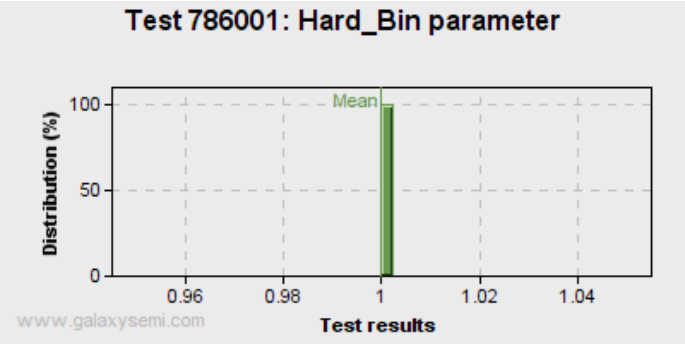
Test	78
Name	Functional_T8 A8 0
Test type	Parametric
Low limit	1 ns
High limit	100 ns
Exec / Fails	30 / 5 (16.67%)
Mean	**104.067 ns**
Sigma	540.921 ns
Range	2972 ns
Cp / Cpk	0.0305 / −0.0025 ....=&gt Warning: Process is over the high limit
Samples	30



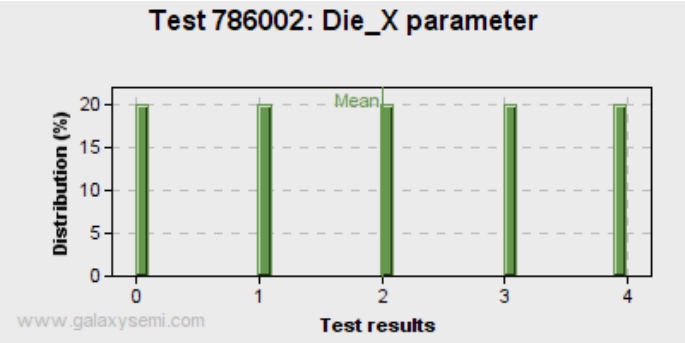
Test	786000
Name	Soft_Bin parameter
Test type	–
Low limit	n/a .
High limit	n/a .
Exec / Fails	30 / 0 (0.00%)
Mean	1
Sigma	0
Range	0
Cp / Cpk	n/a . / n/a .
Samples	30



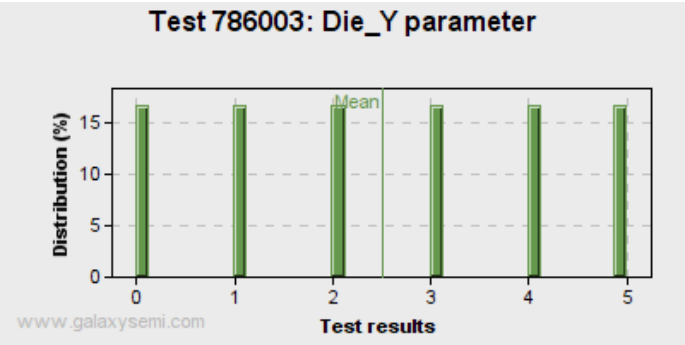
Test	786001
Name	Hard_Bin parameter
Test type	–
Low limit	n/a .
High limit	n/a .
Exec / Fails	30 / 0 (0.00%)
Mean	1
Sigma	0
Range	0
Cp / Cpk	n/a . / n/a .
Samples	30



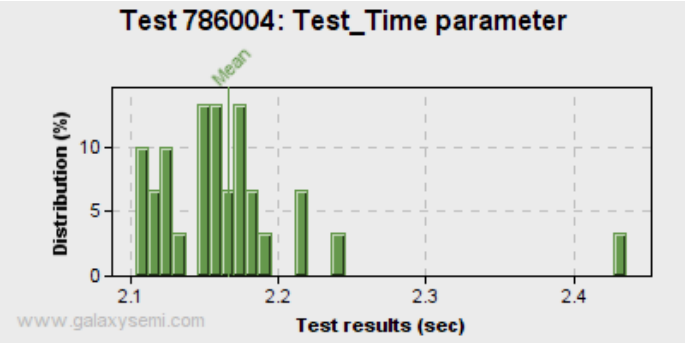
Test	786002
Name	Die_X parameter
Test type	–
Low limit	n/a .
High limit	n/a .
Exec / Fails	30 / 0 (0.00%)
Mean	2
Sigma	1.43839
Range	4
Cp / Cpk	n/a . / n/a .
Samples	30



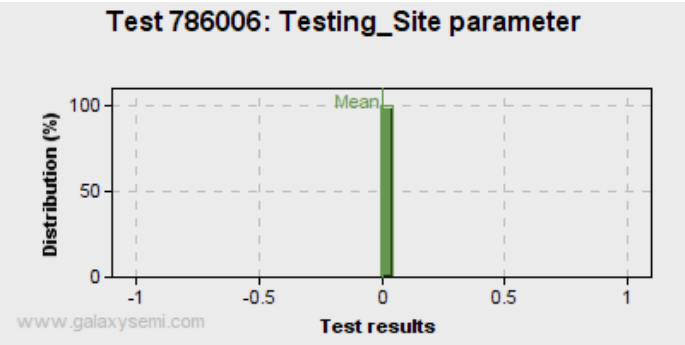
Test	786003
Name	Die_Y parameter
Test type	–
Low limit	n/a .
High limit	n/a .
Exec / Fails	30 / 0 (0.00%)
Mean	2.5
Sigma	1.73702
Range	5
Cp / Cpk	n/a . / n/a .
Samples	30



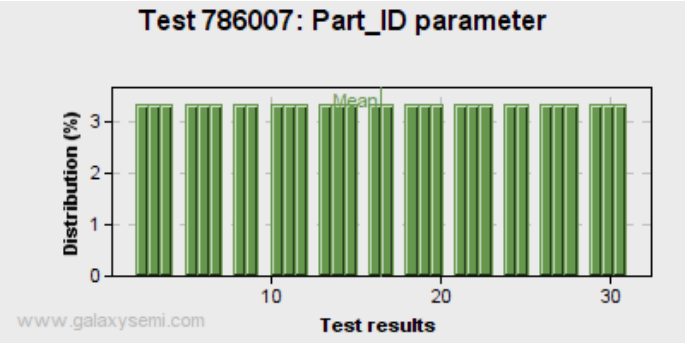
Test	786004
Name	Test_Time parameter
Test type	–
Low limit	0.0 sec
High limit	n/a .
Exec / Fails	30 / 0 (0.00%)
Mean	2.16657 sec
Sigma	0.061458 sec
Range	0.332 sec
Cp / Cpk	n/a . / 11.75
Samples	30



Test	786006
Name	Testing_Site parameter
Test type	–
Low limit	n/a .
High limit	n/a .
Exec / Fails	30 / 0 (0.00%)
Mean	0
Sigma	0
Range	0
Cp / Cpk	n/a . / n/a .
Samples	30



Test	786007
Name	Part_ID parameter
Test type	–
Low limit	n/a .
High limit	n/a .
Exec / Fails	30 / 0 (0.00%)
Mean	16.5
Sigma	8.80341
Range	29
Cp / Cpk	n/a . / n/a .
Samples	30



Pareto of Tests Cp

Test	Name	Cp	Test Cp Chart
78	Functional_T8 A8 0	0.0305	

Shows all Cp <= 1.7 (Defined in Options , section 'Pareto/Define Cp cut−off limit')

Pareto of Tests Cpk

Test	Name	Cpk	Test Cpk Chart
78	Functional_T8 A8 0	−0.0025	

Shows all Cpk <= 1.3 (Defined in Options , section 'Pareto/Define Cp cut−off limit')

Pareto of Tests failures

Test	Name	Failing Bin	Failures count	Yield Loss	Fail contribution	Test Fail rate	Failures Chart
78	Functional_T8 A8 0	–	5	16.1 %	n/a	16.7 %	
–	**Cumul. of failures**	–	**5**	**16.1 %**	**0.0 %**	**16.7 %**	

–– Yield loss: number of failed test executions / number of parts
–– Fail contribution: number of failed test executions / number of parts failed
–– Test Fail rate: number of failed test executions / number of test executions

Pareto of Functional Failure Signatures (pins tested in parallel)

Total devices tested: **31**
Total patterns detected: **1**

Fail count	% of failures	% of tested	Functional Failure signatures (tested pins failing together)
5	100.00 %	16.13 %	Functional_T8 A8 0 (Test 78)
5	**100 %**	**–**	**Total failures detected**

Shows first 25 % of the failure signatures (Defined in Options, section 'Pareto/Define Failure Signatures cut−off limit')

Pareto of Parametric Failure Signatures (tests failing concurrently)

No Parametric failure signature detected

Pareto of Software Bins

Software Binning	Bin Name	Count	Percentage	Software Binning Chart
1	–	31	100.0 %	
Cumul.	Cumul.	31	100.0%	

Pareto of Hardware Bins

Hardware Binning	Bin Name	Count	Percentage	Hardware Binning Chart
1	–	31	100.0 %	
Cumul.	Cumul.	31	100.0%	

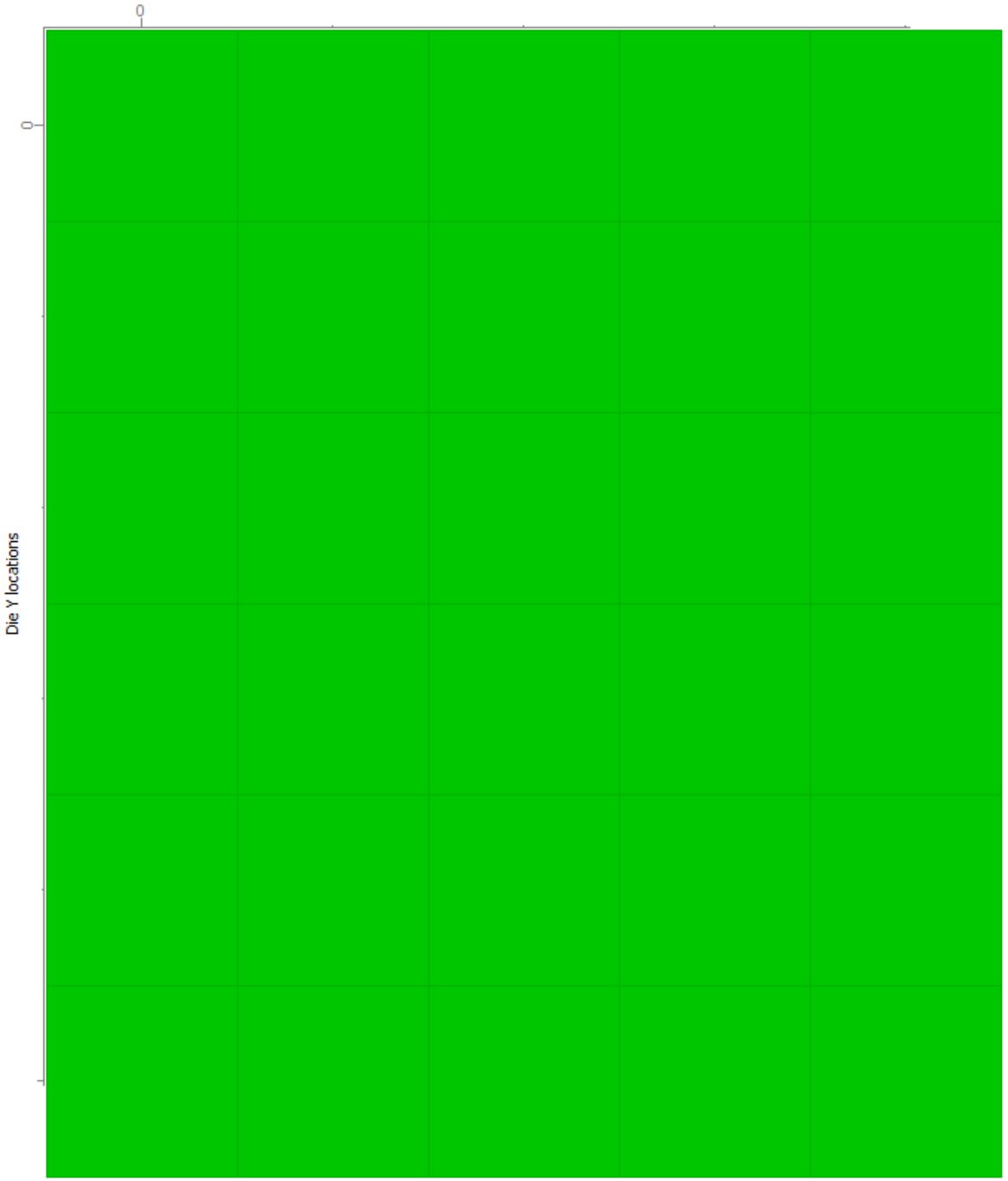
Wafermaps & Strip Maps

Map type	Show Software bins
Devices tested (with retests)	31
Total physical parts tested	30 (only applies to Wafermaps)

List of Individual Maps

Top 10 Software Binning	1
Color	
Pass/Fail	P
Percentage	100.0%
Total count	31

Map style	STRIP map (parts tested are PACKAGED DEVICES!)
Total physical parts tested	30
Parts processed	All Data / parts (any Bin)
Data from Sites	All sites
Strip started	Tue Sep 03 23:15:39 2024
Strip ended	Tue Sep 03 23:24:56 2024
Wafer tested in	9 minutes 17 seconds
Average device test time	17.968 sec.
Map dimensions	LowX=0, LowY=0, HighX=4, HighY=5


0
0
Die Y locations

Run 1, Run 2,...

Software Binning Summary

Software Binning	Bin Name	Pass/ Fail	Total count	Percentage	Software Binning Chart
1	–	P	31	100.0 %	
All PASS Bins	**All PASS Bins**	P	**31**	**100.0 %**	
ALL Bins	**ALL Bins**	–	**31**	**100.0 %**	

Hint: From the 'Options' tab in the 'Binning' section, you can configure how to compute the binning (from summary or samples)

Hardware Binning Summary

Hardware Binning	Bin Name	Pass/ Fail	Total count	Percentage	Hardware Binning Chart
1	–	P	31	100.0 %	
All PASS Bins	All PASS Bins	P	31	100.0 %	
ALL Bins	ALL Bins	–	31	100.0 %	

Hint: From the 'Options' tab in the 'Binning' section, you can configure how to compute the binning (from summary or samples)

Message Log

No log message to report

Global Information

Report from	Teradyne–Examinator–Pro+ – V8.1.5 – www.galaxysemi.com
Report created	Tue Sep 03 11:26:05 2024
Data processed	176.6 KB (180853 bytes)
Processing time	0.97 second
Processing speed	185.9 KB/sec
Examinator expires	Sun Sep 3 2034
(null)	–
File name	C:/Users/rahmana/OneDrive – Teradyne/Desktop/New Hire/New Hire Tech/UFP New Hire Train/Project 1/i8243/results_v3_50loops.std
Tests mapping file	n/a

Setup time	Tue Sep 03 23:22:37 2024
Start time	Tue Sep 03 23:15:39 2024
End time	Tue Sep 03 23:24:56 2024
Test duration	9 minutes 17 seconds
Product	n/a
Program	rahmana_i8243_p1.igxl
Revision	n/a
Lot	n/a
Sub−Lot	n/a
WaferID	n/a
Parts processed	All Data / parts (any Bin)
Data from Sites	All sites
Test time (GOOD parts)	2.167 sec. (excludes tester idle time)
Test time (ALL parts)	2.167 sec. (excludes tester idle time)
Average test time	17.968 sec. / device (includes tester idle time between parts)
Total parts tested	31 − Includes parts retested (if any)
Good parts (Yield)	31 (100.00%) − Includes parts retested (if any)
Bad parts (Yield loss)	0 (0.00%) − Includes parts retested (if any)
Parts retested	n/a .
Parts aborted	0 (0.00%)
(null)	−
STDF Version	4.0
Tester name	SNG−UFP−789
Tester type	UltraFLEXplus
Station	1
Part type	n/a
Operator	rahmana
Exec_type	IG−XL
Exec_version	10.30.10_uflx (P1.11)
TestCode	n/a
Test Temperature	n/a
User Text	n/a
Aux_file	n/a
Package type	n/a
Per_freq	n/a
Spec_name	n/a
Spec_version	n/a
Family ID	n/a

Date code	n/a
Design Rev	n/a
Facility ID	n/a
Floor ID	n/a
Proc ID	n/a
Flow ID	n/a
Setup ID	n/a
Eng ID	n/a
ROM code	n/a
Serial #	n/a
Super user name	n/a
Handler/Prober	n/a
(null)	–
Site details	Site# 0

Global Options

Test# policy	Never merge tests with identical test number if test name not matching
Data Cleaning	None (keep all data)
Statistics computation	From samples data (if any), otherwise from summary
Binning computation	From summary data (if any), otherwise from samples
Cp,Cpk computation	Use standard Sigma formula
Mean drift formula	Percentage of value drift